



INFORMATION DISCLOSURE CITATION PTO-1449	CUSTOMER NUMBER 45114	ATTORNEY'S DKT No. H1105D	APPLICATION No. 10/602,061
		APPLICANT(S) Shibly S. Ahmed et al.	
		FILING DATE June 24, 2003	GROUP 2812

U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
RP	6,472,258	10/2002	Adkisson et al.	438	192	

FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
EXAMINER	DATE CONSIDERED
RP Rmpes	4-26-05

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).

INFORMATION DISCLOSURE CITATION PTO-1449		Customer Number 26615	ATTORNEY'S DKT No. H1105D		APPLICATION No. 10/602,061	
			APPLICANT(S) Shibly S. AHMED et al.			
			FILING DATE June 24, 2003		GROUP <u>Unassigned</u> <i>2812</i>	

U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
<i>RP</i>	5,563,082	10-08-96	Mukai	437	41	12-23-94
<i>RP</i>	6,413,802 B1	07-02-02	Hu et al.	438	151	10-23-00

FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
<i>RP</i>	Leland Chang et al.: "Gate Length Scaling and Threshold Voltage Control of Double-Gate MOSFETs," IEDM, December 10, 2000, pages 719-722.

EXAMINER <i>Rm Pompey</i>	DATE CONSIDERED <i>4-26-05</i>
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).